



UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
 UNITED STATES PATENT AND TRADEMARK OFFICE
 WASHINGTON, D.C. 20231
www.uspto.gov



Bib Data Sheet

CONFIRMATION NO. 8779

SERIAL NUMBER 09/891,511	FILING DATE 06/27/2001 RULE	CLASS 438	GROUP ART UNIT 2812	ATTORNEY DOCKET NO. 010819
-----------------------------	-----------------------------------	--------------	------------------------	----------------------------------

APPLICANTS

Mamoru Nakasui, Kanagawa, JAPAN;
 Nobuharu Noji, Kanagawa, JAPAN;
 Tohru Satake, Kanagawa, JAPAN;
 Masahiro Hatakeyama, Kanagawa, JAPAN;
 Toshifumi Kimba, Kanagawa, JAPAN;
 Hirosi Sobukawa, Kanagawa, JAPAN;
 Shoji Yoshikawa, Tokyo, JAPAN;
 Takeshi Murakami, Tokyo, JAPAN;
 Kenji Watanabe, Kanagawa, JAPAN;
 Tsutomu Karimata, Kanagawa, JAPAN;
 Shin Oowada, Kanagawa, JAPAN;
 Mutsumi Saito, Kanagawa, JAPAN;
 Yuichiro Yamazaki, Tokyo, JAPAN;
 Takamitsu Nagai, Kanagawa, JAPAN;
 Ichiro Nagahama, Kanagawa, JAPAN;

** CONTINUING DATA *none* *JB*** FOREIGN APPLICATIONS *JB*

JAPAN 2000-193104 06/27/2000
 JAPAN 2000-229101 07/28/2000
 JAPAN 2000-335934 11/02/2000
 JAPAN 2001-11218 01/19/2001
 JAPAN 2001-31901 02/08/2001
 JAPAN 2001-31906 02/08/2001
 JAPAN 2001-33599 02/09/2001
 JAPAN 2001-35069 02/13/2001
 JAPAN 2001-158662 05/28/2001
 JAPAN 2001-162041 05/30/2001
 JAPAN 2001-189304 06/22/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 08/29/2001

Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after <i>met</i>	STATE OR COUNTRY JAPAN	SHEETS DRAWING 50	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13
Verifier and Acknowledged <i>Jack Newman</i> <i>JB</i>					
Examiner's Signature <i>Jack Newman</i> <i>JB</i>					
ADDRESS 23850					
TITLE Inspection system by charged particle beam and method of manufacturing devices using the system A <i>ees</i>					

BEST AVAILABLE COPY

BEST AVAILABLE COPY